

**Search Notes**

Application/Control No.

10/711,445

Examiner

David Goodwin

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2818

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
438/164, 165, 197, 211, 257, 663, 264, 595, 594, 682, 695, 755, 770, 780	4/18/2006	DJG